

FORM PTO-1449  
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

SERIAL NO.

TI-31076

09/864,509

## LIST OF DOCUMENTS CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Lee D. Whetsel

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5/23/2001

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2133

MAY 27 2005

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
CB	3,633,100	1/4/1972	Heilweil, et al.	324	73	5/12/1970
	3,651,315	3/21/1972	Collins	235	151.31	4/29/1970
	3,657,527	4/18/1972	Kassabgi, et al.	235	153	10/16/1969
	3,723,868	3/27/1973	Foster	324	73 AT	1/21/1972
	3,739,193	6/12/1973	Pryor	307	205	1/11/1971
	3,789,359	1/29/1974	Clark, Jr., et al.	340	146.1D	10/4/1972
	3,824,678	7/23/1974	Harris, et al.	29	578	8/31/1970
	3,826,909	7/30/1974	Ivashin	235	153 AC	3/29/1973
	3,831,149	8/20/1974	Job	340	172.5	2/14/1973
	3,838,264	9/24/1974	Maker	235	153 AM	11/23/1971
	3,873,818	3/25/1975	Barnard	253	153 AC	10/29/1973
	3,976,940	8/24/1976	Chau, et al.	324	73 R	2/25/1975
	4,023,142	5/10/1977	Woessner	340	172.5	4/14/1975
	4,066,882	1/3/1978	Esposito	235	302	8/16/1976
	4,086,375	4/25/1978	LaChapelle, Jr., et al.	427	90	11/7/1975
	4,092,733	5/30/1978	Coontz, et al.	365	200	5/7/1976
	4,108,359	8/22/1978	Proto	235	304	3/30/1977
	4,146,835	3/27/1979	Chnapko, et al.	324	73 R	3/8/1978
	4,161,276	7/17/1979	Sacher, t al.	235	302	3/1/1978
	4,216,539	8/5/1980	Raymond, et al.	371	20	5/5/1978
	4,242,751	12/30/1980	Henckels, et al.	371	26	2/24/1976
	4,264,807	4/28/1981	Moen, et al.	235	92 GD	4/9/1979
	4,268,902	5/19/1981	Berglund, et al.	364	200	10/23/1978
	4,286,173	8/25/1981	Oka, et al.	307	440	3/27/1978
	4,308,616	12/29/1981	Timoc	371	23	5/29/1979
	4,309,767	1/5/1982	Andow, et al.	371	24	8/21/1979
	4,312,066	1/19/1982	Bantz, et al.	371	16	12/28/1979
	4,339,710	7/13/1982	Hapke	324	73 R	2/12/1979
	4,357,703	11/2/1982	Van Brunt	371	15	10/9/1980
	4,365,334	12/21/1982	Smith, et al.	371	27	2/9/1981
	4,366,478	12/28/1982	Masuda, et al.	340	825	1/5/1981
	4,390,969	6/1/1983	Hayes	395	550	4/21/1980
	4,426,697	1/1/1984	Petersen, et al.	340	825.52	1/24/1981
CB	4,433,413	2/21/1984	Fasang	371	25	10/22/1981

EXAMINER

Cynthia R. Burt

DATE CONSIDERED

8-11-05

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FORM PTO-1449  
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

SERIAL NO.

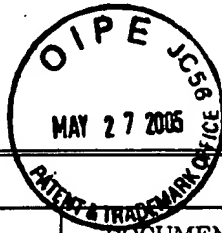
T1-31076

09/864,509

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## U.S. PATENT DOCUMENTS

+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
CB	4,439,858	3/27/1984	Petersen	371	20	5/28/1981
	4,441,075	4/3/1984	McMahon	324	73 R	7/2/1981
	4,483,002	11/13/1984	Groom, Jr., et al.	371	29	4/19/1982
	4,484,329	11/20/1984	Slamka, et al.	371	25	8/10/1981
	4,488,259	12/11/1984	Mercy	364	900	10/29/1982
	4,493,077	1/8/1985	Agrawal, et al.	371	25	9/9/1982
	4,494,066	1/15/1985	Goel, et al.	324	73 R	7/2/1981
	4,498,172	2/5/1985	Bhavsar	371	25	7/26/1982
	4,503,536	3/5/1985	Panzer	371	25	9/16/1982
	4,504,784	3/12/1985	Goel, et al.	324	73R	7/2/1981
	4,513,373	4/1/1985	Sheets	364	200	12/28/1982
	4,513,418	4/23/1985	Bardell, Jr, et al.	371	25	11/8/1982
	4,514,845	4/30/1985	Starr	371	15	8/23/1982
	4,519,078	5/21/1985	Komonytshy	371	25	9/29/1982
	4,534,028	8/6/1985	Trischler	371	25	12/1/1983
	4,553,090	11/12/1985	Hatano, et al.	324	73 AT	7/23/1980
	4,575,674	3/11/1986	Bass, et al.	324	73 R	7/1/1983
	4,577,318	3/18/1986	Whitacre, et al.	371	1	11/14/1983
	4,587,609	5/1/1986	Boudreau, et al.	395	726	7/1/1983
	4,594,711	6/10/1986	Thatte	371	25	11/10/1983
	4,597,042	6/24/1986	d'Angeac	364	200	9/13/1983
	4,597,080	6/24/1986	Thatte, et al.	371	25	11/14/1983
	4,598,401	7/1/1986	Whelan	371	25	6/25/1984
	4,601,034	7/15/1986	Sridhar	371	25	3/30/1984
	4,602,210	7/22/1986	Fasang, et al.	324	73	12/28/1984
	4,612,499	9/16/1986	Andresen, et al.	324	73 R	11/7/1983
	4,615,029	9/30/1986	Hu, et al.	370	89	12/3/1984
	4,618,956	10/21/1986	Horst	371	68	9/29/1983
	4,620,302	10/28/1986	Binoeder, et al.	371	1	1/6/1984
	4,621,363	11/4/1986	Blum	371	25	12/6/1984
	4,627,018	12/1/1986	Trost, et al.	395	476	9/8/1983
	4,628,511	12/9/1986	Stitzlein, et al.	371	22	2/25/1982
OB	4,635,193	1/6/1987	Moyer, et al.	364	200	6/27/1984
	4,635,261	1/6/1987	Anderson, et al.	371	25	1/26/1985

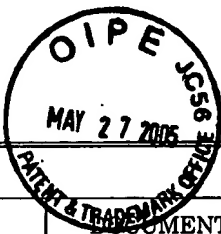
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FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. TI-31076		SERIAL NO. 09/864,509	
LIST OF DOCUMENTS CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT Lee D. Whetsel  FILING DATE 5/23/2001      GROUP 2133			
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U.S. PATENT DOCUMENTS							
+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)	
cb	4,638,313	1/20/1987	Sherwood, et al.	340	825.52	11/8/1984	
	4,642,561	2/10/1987	Groves, et al.	324	73 R	6/13/1983	
	4,646,298	2/1/1987	Laws, et al.	371	16	5/1/1984	
	4,646,299	2/24/1987	Schinabeck, et al.	371	20	8/1/1983	
	4,651,088	3/17/1987	Sawada	324	73R	5/6/1985	
	4,669,061	5/26/1987	Bhavsar	365	154	12/21/1984	
	4,672,307	6/9/1987	Breuer, et al.	324	73 R	12/20/1985	
	4,674,089	6/16/1987	Poret, et al.	371	25	4/16/1985	
	4,679,192	7/1/1987	Vanbrabant	340	825.52	1/24/1986	
	4,680,539	7/14/1987	Tsai	324	73	12/30/1983	
	4,680,733	7/14/1987	Duforestel	364	900	10/29/1984	
	4,683,569	7/28/1987	Rubin	371	25	10/21/1985	
	4,687,988	8/18/1987	Eichelberger, et al.	324	73 AT	6/24/1985	
	4,694,293	9/15/1987	Sugiyama, et al.	340	825.68	9/16/1985	
	4,698,588	10/6/1987	Hwang, et al.	324	73 R	10/23/1985	
	4,701,916	10/20/1987	Naven, et al.	371	15	3/17/1986	
	4,701,920	10/20/1987	Resnick, et al.	371	25	11/8/1985	
	4,701,921	10/20/1987	Powell, et al.	371	25	10/23/1985	
	4,710,931	12/1/1987	Bellay, et al.	371	25	10/23/1985	
	4,710,932	12/1/1987	Hiroshi	371	25	1/15/1986	
	4,710,933	12/1/1987	Powell, et al.	371	25	10/23/1985	
	4,734,921	3/29/1988	Giangano, et al.	377	72	11/25/1986	
	4,740,970	4/26/1988	Burrows, et al.	371	15	12/11/1985	
	4,743,841	5/10/1988	Takeuchi	324	73 R	5/20/1985	
	4,745,355	5/17/1988	Eichelberger, et al.	324	73 R	6/24/1985	
	4,752,929	6/21/1988	Kantz, et al.	371	21	3/25/1986	
	4,759,019	7/19/1988	Bentley, et al.	371	3	7/10/1986	
	4,763,066	8/9/1988	Yeung, et al.	324	73R	7/23/1986	
	4,764,926	8/16/1988	Knight, et al.	371	25	12/11/1985	
	4,777,616	10/11/1988	Moore, et al.	364	900	5/12/1986	
4,783,785	11/8/1988	Hanta	371	25	1/5/1987		
4,788,683	11/29/1988	Hester, et al.	371	20	1/14/1986		
4,791,358	12/13/1988	Sauerwald, et al.	324	73 R	9/2/1986		
cb	4,799,004	1/17/1989	Mori	324	73 R	1/25/1988	

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U.S. PATENT DOCUMENTS							
+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)	
CS	4,799,052	1/1/1989	Near, et al.	340	825.52	1/13/1986	
	4,800,418	1/24/1989	Natsui	357	68	9/6/1984	
	4,801,870	1/31/1989	Eichelberger, et al.	324	73R	6/24/1985	
	4,802,163	1/31/1989	Hirabayshi	371	15	12/29/1986	
	4,808,844	2/28/1989	Ozaki, et al.	307	243	4/17/1986	
	4,811,299	3/7/1989	Miyazawa, et al.	365	201	4/22/1987	
	4,812,678	3/14/1989	Abe	307	443	3/23/1987	
	4,817,093	3/28/1989	Jacobs, et al.	371	25	6/18/1987	
	4,819,234	4/4/1989	Huber	371	19	5/1/1987	
	4,821,269	4/11/1989	Jackson, et al.	371	16	10/23/1986	
	4,825,439	4/25/1989	Sakashita, et al.	371	15	8/18/1987	
	4,833,395	5/23/1989	Sasaki, et al.	324	73 R	10/23/1987	
	4,833,676	5/23/1989	Koo	371	15	7/30/1987	
	4,855,954	8/8/1989	Turner, et al.	365	185	3/4/1985	
	4,857,835	8/15/1989	Whetsel	324	73	11/5/1987	
	4,860,288	8/22/1989	Teske, et al.	371	1	10/23/1987	
	4,860,290	8/22/1989	Daniels, et al.	371	25	6/2/1987	
	4,862,071	8/29/1989	Sato, et al.	324	73 R	11/18/1988	
	4,862,072	8/29/1989	Harris, et al.	324	73 R	9/8/1988	
	4,864,570	9/5/1989	Savaglio, et al.	371	22.4	6/29/1987	
	4,864,579	9/5/1989	Kishida, et al.	371	22.3	8/3/1987	
	4,866,508	9/12/1989	Eichelberger, et al.	357	74	9/26/1986	
	4,870,345	9/26/1989	Tomioka, et al.	371	22.3	8/3/1987	
	4,872,169	10/3/1989	Whetsel	371	22.3	3/6/1987	
	4,875,003	10/17/1989	Burke	324	73 R	2/21/1989	
	4,878,168	10/31/1989	Johnson, et al.	364	200	10/29/1986	
	4,879,717	11/7/1989	Sauerwald, et al.	371	22.3	9/2/1986	
	4,887,262	12/12/1989	van Veldhuizen	370	85.1	3/15/1988	
	4,887,267	12/12/1989	Kanuma	371	22.3	12/28/1987	
	4,893,072	1/9/1990	Matsumoto	371	223	6/22/1988	
4,894,830	1/16/1990	Kawai	371	22.3	1/19/1988		
4,896,262	1/23/1990	Wayama, et al.	364	200	2/22/1985		
CB	4,897,842	1/30/1990	Herz, et al.	371	22.4	11/5/1987	

EXAMINER <i>Cynthia Britt</i>	DATE CONSIDERED <i>8-11-05</i>
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U.S. PATENT DOCUMENTS							
+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)	
DB	4,899,273	2/6/1990	Omoda, et al.	364	200	12/10/1986	
	4,903,266	2/20/1990	Hack	371	21.2	4/29/1988	
	4,907,230	3/6/1990	Heller, et al.	371	22.1	2/29/1988	
	4,910,735	3/20/1990	Yamashita	371	22.4	12/17/1987	
	4,912,633	3/27/1990	Schweizer, et al	364	200	10/24/1988	
	4,912,709	3/27/1990	Teske, et al.	371	22.1	10/23/1987	
	4,918,379	4/17/1990	Jongepier	324	73.1	8/31/1988	
	4,924,468	5/8/1990	Horak, et al.	371	22.1	11/16/1988	
	4,926,425	5/15/1990	Hedtke, et al.	371	22.6	6/9/1988	
	4,929,889	5/29/1990	Seiler, et al.	371	22.3	6/13/1988	
	4,930,216	6/5/1990	Nelson	29	854	3/10/1989	
	4,931,722	6/5/1990	Stoica	371	22.5	11/7/1985	
	4,931,723	6/5/1990	Jeffrey, et al.	371	22.3	12/18/1985	
	4,935,868	6/1/1990	DuLac	364	200	11/28/1988	
	4,937,826	6/26/1990	Gheewala, et al.	371	22.1	9/9/1988	
	4,943,966	7/24/1990	Giunta, et al.	371	11.1	4/8/1988	
	4,945,536	7/31/1990	Hancu	371	22.3	9/9/1988	
	4,947,106	8/7/1990	Chism	324	73.1	3/31/1988	
	4,947,357	8/7/1990	Stewart, et al.	371	22.3	2/24/1988	
	4,956,602	9/11/1990	Parrish	324	158 R	2/14/1989	
	4,961,053	10/2/1990	Krug	324	158 R	7/24/1985	
	4,969,121	11/6/1990	Chan, et al.	364	900	3/2/1987	
	4,974,192	11/27/1990	Face, et al	364	900	7/23/1987	
	4,974,226	11/27/1990	Fujimori, et al.	371	22.3	9/22/1988	
	4,989,209	1/29/1991	Littlebury, et al.	371	22.1	3/24/1989	
	4,992,985	2/12/1991	Miyazawa, et al.	365	201	4/22/1987	
	5,001,713	3/19/1991	Whetsel	371	22.3	2/8/1989	
	5,008,618	4/16/1991	Van Der Star	324	158 R	1/23/1990	
	5,008,885	4/16/1991	Huang, et al.	371	3	12/29/1988	
	5,012,185	4/30/1991	Ohfuji	324	158 R	10/16/1989	
5,014,186	5/1/1991	Chisholm	395	850	8/1/1986		
5,023,872	6/11/1991	Annamalai	371	5.1	3/25/1988		

EXAMINER <div style="font-family: cursive; font-size: 1.2em; margin-top: 10px;">Cynthia Brutt</div>	DATE CONSIDERED <div style="font-family: cursive; font-size: 1.2em; margin-top: 10px;">8-11-05</div>
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<div style="font-size: 2em; font-family: cursive;">CB</div>	5,042,005	8/20/1991	Miller, et al.	364	900	8/19/1988
	5,048,021	9/10/1991	Jarwala, et al.	371	22.3	8/28/1989
	5,051,996	9/24/1991	Bergeson, et al.	371	22.4	3/27/1989
	5,053,949	10/1/1991	Allison, et al.	364	200	4/3/1989
	5,054,024	10/1/1991	Whetsel	371	22.3	8/9/1989
	5,056,093	10/8/1991	Whetsel	371	22.3	8/9/1989
	5,056,094	10/8/1991	Whetsel	371	25.1	6/9/1989
	5,070,296	12/3/1991	Priebe	324	73.1	6/22/1990
	5,070,297	12/3/1991	Kwon, et al.	324	158 P	6/4/1990
	5,077,740	12/31/1991	Kanuma	371	22.3	1/30/1989
	5,084,814	1/28/1992	Vaglica, et al.	395	325	10/30/1987
	5,084,814	1/28/1992	Whetsel	371	22.3	9/7/1988
	5,090,015	2/18/1992	Dabbish, et al.	371	22.5	2/6/1989
	5,090,035	2/18/1992	Murase	377	72	1/22/1991
	5,103,450	4/7/1992	Whetsel	714	724	2/8/1989
	5,107,148	4/21/1992	Millman	307	473	4/12/1991
	5,107,489	4/1/1992	Brown, et al.	370	58.2	10/30/1989
	5,109,190	4/28/1992	Sahashita, et al.	324	158 R	2/22/1991
	5,109,383	4/28/1992	Chujo	371	22.3	9/1/1989
	5,115,191	5/19/1992	Yoshimori	324	158 R	6/11/1991
	5,115,435	5/1/1992	Langford, II, et al.	371	22.1	10/19/1989
	5,126,286	6/30/1992	Chance	437	203	10/5/1990
	5,128,664	7/1/1992	Bishop	340	825.52	5/5/1986
	5,130,988	7/1/1992	Wilcox, et al.	371	22.3	9/17/1990
	5,132,635	7/1/1992	Kennedy	371	22.3	3/5/1991
	5,133,062	7/1/1992	Joshi, et al.	395	500	3/6/1986
	5,134,314	7/28/1992	Wehrmacher	307	443	12/18/1990
	5,150,044	9/1/1992	Hashizume, et al.	324	158 R	3/22/1991
	5,150,047	9/22/1992	Saito, et al.	324	158 R	7/17/1990
	5,155,432	10/13/1992	Mahoney	324	158 R	10/7/1987
5,159,465	10/1/1992	Maemura, et al.	326	73	10/5/1988	
5,161,160	11/3/1992	Yaguchi, et al.	371	22.3	2/1/1990	
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	5,170,398	12/8/1992	Fujieda, et al.	371	27	7/18/1990
	5,172,377	12/1/1992	Robinson, et al.	371	22.3	9/7/1990
	5,173,906	12/22/1992	Dreibelbis, et al.	371	22.5	8/31/1990
	5,175,447	12/29/1992	Kawasaki, et al.	307	480	4/19/1991
	5,187,795	2/1/1993	Balmforth, et al.	395	800	1/27/1989
	5,191,653	3/1/1993	Banks, et al.	395	275	12/28/1990
	5,202,625	4/13/1993	Farwell	324	158 R	7/3/1991
	5,206,545	4/27/1993	Huang	307	443	2/5/1991
	5,210,759	5/11/1993	DeWitt, et al.	371	22.3	11/19/1990
	5,214,760	5/1/1993	Hammond, et al.	395	250	8/26/1988
	5,214,774	5/1/1993	Welsch, et al.	455	11.1	7/30/1990
	5,218,702	6/1/1993	Kirtland	395	298	7/6/1988
	5,222,068	6/22/1993	Burchard	371	22.3	3/13/1992
	5,241,265	8/31/1993	McDonnell, et al.	324	158 R	3/26/1992
	5,241,266	8/31/1993	Ahmad, et al.	324	158 R	4/10/1992
	5,252,917	10/12/1993	Kadowaki	324	158 R	4/24/1991
	5,254,942	10/19/1993	D'Souza, et al.	324	158 R	4/25/1991
	5,258,985	11/2/1993	Spence, et al.	371	22.4	11/12/1991
	5,260,949	11/9/1993	Hashizume, et al.	371	22.3	12/14/1990
	5,276,807	1/1/1994	Kodoma, et al.	395	309	4/13/1987
	5,278,494	1/11/1994	Obigane	324	158 F	2/19/1992
	5,279,975	1/18/1994	Devereaux, et al.	437	8	2/7/1992
	5,286,656	2/15/1994	Keown, et al.	437	7	11/2/1992
	5,291,025	3/1/1994	Smith	250	561	11/30/1992
	5,297,277	3/22/1994	Dein, et al.	395	575	8/31/1990
	5,303,148	4/12/1994	Mattson, et al.	364	413.01	11/27/1987
	5,313,158	5/17/1994	Joosten, et al.	324	158 R	1/12/1993
	5,315,241	5/24/1994	Ewers	324	158 R	9/18/1991
	5,317,205	5/31/1994	Sato	307	443	6/2/1992
5,319,754	6/1/1994	Meinecke, et al.	395	325	10/3/1991	
5,321,322	6/14/1994	Verheyen, et al.	307	465.1	3/24/1993	
EXAMINER <i>Cynthia Butt</i>			DATE CONSIDERED <i>8-11-05</i>			
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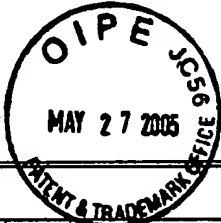
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PATENT & TRADEMARK OFFICE

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	5,329,471	7/12/1994	Swoboda, et al.	364	578	6/2/1987	
	5,334,857	8/2/1994	Mennitt, et al.	257	48	4/6/1992	
	5,343,478	8/1/1994	James, et al.	371	22.3	11/27/1991	
	5,353,308	10/4/1994	Whetsel	371	22.3	8/6/1990	
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	5,366,906	11/22/1994	Wojnarowski, et al.	437	8	10/16/1992	
	5,371,390	12/6/1994	Mohsen	257	209	11/4/1992	
	5,377,198	12/27/1994	Simpson, et al.	371	22.3	11/27/1991	
	5,388,216	2/1/1995	Oh	395	849	10/3/1991	
	5,389,556	2/14/1995	Rostoker, et al.	437	8	7/2/1992	
	5,389,873	2/14/1995	Ishii, et al.	324	158.1	5/18/1993	
	5,390,131	2/14/1995	Rohrbaugh, et al.	364	490	4/6/1992	
	5,391,984	2/14/1995	Worley	324	158.1	11/1/1991	
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	5,420,874	5/30/1995	Kromer	371	47.1	4/20/1993	
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	5,434,804	7/18/1995	Bock, et al.	364	579	12/29/1993	
	5,442,282	8/15/1995	Rostoker, et al.	324	158.1	7/2/1992	
	5,446,395	8/29/1995	Goto	324	763	9/21/1993	
	5,448,166	9/5/1995	Parker et al.	324	158	1/3/1992	
	5,448,525	9/5/1995	Sturges	365	201	3/10/1994	
	5,448,576	9/5/1995	Russell	371	22.3	10/29/1992	
	5,450,415	9/12/1995	Kamada	371	22.3	11/19/1993	
	5,453,992	9/26/1995	Whetsel	371	22.3	8/2/1993	
	5,457,400	10/10/1995	Ahmad, et al.	324	763	4/10/1992	
5,469,473	11/21/1995	McClear, et al.	375	219	4/15/1994		
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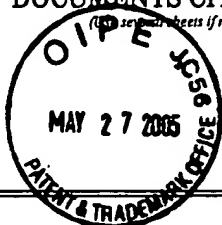
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	5,491,699	2/13/1996	Scheuermann, et al.	371	22.1	2/2/1994		
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	5,497,378	3/5/1996	Amini et al.	714	727	11/2/1993		
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	5,532,174	7/2/1996	Corrigan	437	8	4/22/1994		
	5,534,786	7/9/1996	Kaneko, et al.	324	760	2/22/1995		
	5,535,222	7/9/1996	Le	371	22	12/23/1993		
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	5,541,935	7/30/1996	Waterson	371	22.5	5/26/1995		
	5,544,174	8/6/1996	Abend	371	22.3	3/17/1994		
	5,548,781	8/11/1996	Huang	395	831	7/8/1993		
	5,550,843	8/27/1996	Yee	371	22.3	4/1/1994		
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	5,568,492	10/22/1996	Flint, et al.	371	22.1	6/6/1994		
	5,568,493	10/22/1996	Morris	324	73	10/16/1992		
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	5,592,493	1/7/1997	Crouch et al.	371	22.3	9/13/1994		
5,600,788	2/4/1997	Lofgren et al.	395	183	1/19/1994			
5,608,335	3/4/1997	Taillet	324	763	12/27/1993			
5,608,736	3/4/1997	Bradford, et al.	371	22.3	6/6/1991			
<i>CB</i>	5,610,530	3/11/1997	Whetsel	324	763	10/26/1994		
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	5,659,257	8/19/1997	Lu, et al.	324	763	7/5/1994
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	5,677,915	10/14/1997	Whetsel	371	22.3	8/18/1993
	5,685,004	11/4/1997	Bruce, et al.	395	800	3/6/1990
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	5,719,876	2/17/1998	Warren	371	22.3	8/24/1995
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	5,805,609	9/8/1998	Mote, Jr.	714	726	6/7/1995
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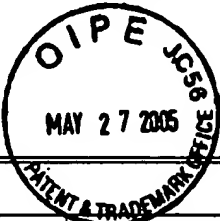
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	5,887,001	3/23/1999	Russell	714	726	12/13/1995	
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	5,905,738	3/18/1999	Whetsel	371	22.4	6/30/1989	
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	5,949,984	9/7/1999	Fujitaka	395	500	12/1/1997	
	5,958,072	9/28/1999	Jacobs, et al.	714	30	1/13/1997	
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	5,968,192	10/19/1999	Kornachuk et al.	714	724	5/9/1997	
	6,000,051	12/7/1999	Nadeau-Dostie et al.	714	727	10/10/1997	
	6,006,343	12/21/1999	Whetsel	714	28	7/30/1993	
	6,028,983	2/22/2000	Jaber	395	183.06	9/19/1996	
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	6,046,600	4/4/2000	Whetsel	324	763	10/31/1995	
	6,055,656	4/25/2000	Wilson, Jr., et al.,	714	724	5/2/1995	
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	6,115,763	9/5/2000	Douskey, et al.	710	72	3/5/1998	
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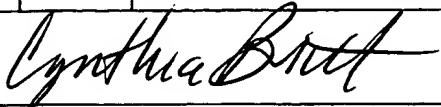


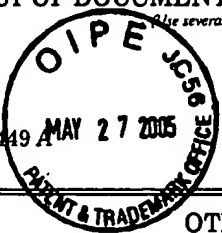

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	EP 0,195,164	9/24/1986	Europe	G01	R31/28	X	
	EP 0,273,821	7/6/1988	Europe	G01	R31/28	X	
	EP 0,310,152	4/5/1989	Europe	G01	R31/28	X	
	EP 0,315,475 A2	10/5/1989	Europe	G01	R31/28	X	
	EP 0,518,550 A2	12/16/1992	Europe	G06F	37586		
	EP 0,522,413 A2	1/13/1993	Europe	G06F	37586		
	EP 0,604,032 A2	6/29/1994	Europe	G06F	37586		
	GB 2,220,272 A	1/4/1990	UK	G01R	31/28		
	GB 2,266,965 A	11/17/1993	UK	G01R	31/28		
	JP 01-038674 A	2/8/1989	Japan	G01R	31/28	X	
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	JP 01-068167 A	3/14/1989	Japan	H04M	3/22	X	
	JP 01-079673(A)	3/24/1989	Japan	G01R31	28	X	
	JP 01-110274	4/26/1989	Japan	G01R31	28	X	
	JP 01-170873	7/5/1989	Japan	G01R31	28	X	
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	JP 02-052165	4/13/1990	Japan	G01R	13/28	X	
	JP 02-062984	3/2/1990	Japan	G01R	31/28	X	
	JP 05-142,298	6/8/1993	Japan	G01	R31/28	X	
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	JP 58-191021 A	11/8/1983	Japan	G06F	36586	X	
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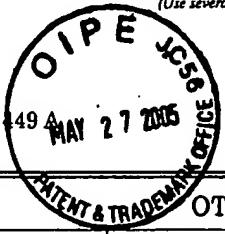
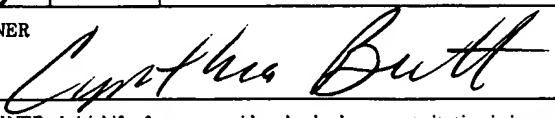
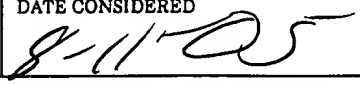
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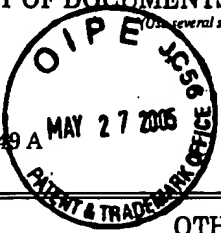


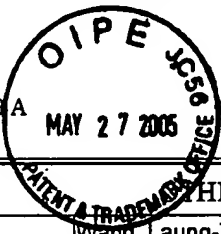
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